

TEST REPORT

Applicant: Lumos Labs International Pte Ltd
Address: 11 Collyer Quay, #17-00, The Arcade, Singapore
049317, Singapore
Equipment Type: Lumos Ultra E-Bike
Model Name: LHEUT-N0 (refer section 2.4)
Brand Name: Lumos
Test Standard: ANSI/IEEE Std 149-1979
Test Date: Aug. 01, 2022
Date of Issue: Sep. 05, 2022

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.



Tested by: Mai Jintian

Checked by: Tolan Tu

Approved by: Wei Yanquan
(Chief Engineer)

Mai Jintian

Tolan Tu

Wei Yanquan

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Sep. 05, 2022</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe West Road, Nanshan District, ShenZhen, GuangDong Province, China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe West Road, Nanshan District, ShenZhen, GuangDong Province, China
Description	All measurement facilities used to collect the measurement data are located at Block B, 1/F, Baisha Science and Technology Park, Shahe West Road, Nanshan District, ShenZhen, GuangDong Province, China

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Lumos Labs International Pte Ltd
Address	11 Collyer Quay, #17-00, The Arcade, Singapore 049317, Singapore
Contact Person	Bilal Raja
Telephone Number	+60 11-2110 9192
E-mail Address	info@lumoshelmet.co

2.2 Manufacturer Information

Manufacturer	Lumos Labs International Pte Ltd
Address	11 Collyer Quay, #17-00, The Arcade, Singapore 049317, Singapore

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	Lumos Ultra E-Bike
Model Name Under Test	LHEUT-N0
Serial Model Name	LHEUT-E0
Model Description	The hardware circuit and software are identical to the basic model. Except the Model Names (this information provided by the customer).
Antenna Type	PCB Antenna
Dimensions	3*10 mm

2.5 Ancillary Equipment

Ancillary Equipment 1	Battery	
	Brand Name	YJ
	Model No.	122540
	Serial No.	N/A
	Capacity	1300 mAh
	Rated Voltage	3.7 V
	Limited Voltage	5.0 V

2.6 Technical Information

Frequency Range	2400MHz ~ 2500MHz
Test Frequencies	2400MHz, 2402MHz, 2404MHz, 2406MHz, 2408MHz, 2410MHz, 2412MHz, 2414MHz, 2416MHz, 2418MHz, 2420MHz, 2422MHz, 2424MHz, 2426MHz, 2428MHz, 2430MHz, 2432MHz, 2434MHz, 2436MHz, 2438MHz, 2440MHz, 2442MHz, 2444MHz, 2446MHz, 2448MHz, 2450MHz, 2452MHz, 2454MHz, 2456MHz, 2458MHz, 2460MHz, 2462MHz, 2464MHz, 2466MHz, 2468MHz, 2470MHz, 2472MHz, 2474MHz, 2476MHz, 2478MHz, 2480MHz, 2482MHz, 2484MHz, 2486MHz, 2488MHz, 2490MHz, 2492MHz, 2494MHz, 2496MHz, 2498MHz, 2500MHz.

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	ANSI/IEEE Std 149-1979	IEEE Standard Test Procedures for Antennas

3.2 Test Verdict

Report Section	Description	Remark
ANNEX A.1	Gain and Efficiency	--
ANNEX B	Radiation Pattern	--

3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Item	Uncertainty
VSWR(S11)	± 0.61
Gain	$\pm 1.92\text{dB}$

4 GENERAL TEST CONFIGURATIONS

4.1 Test Condition

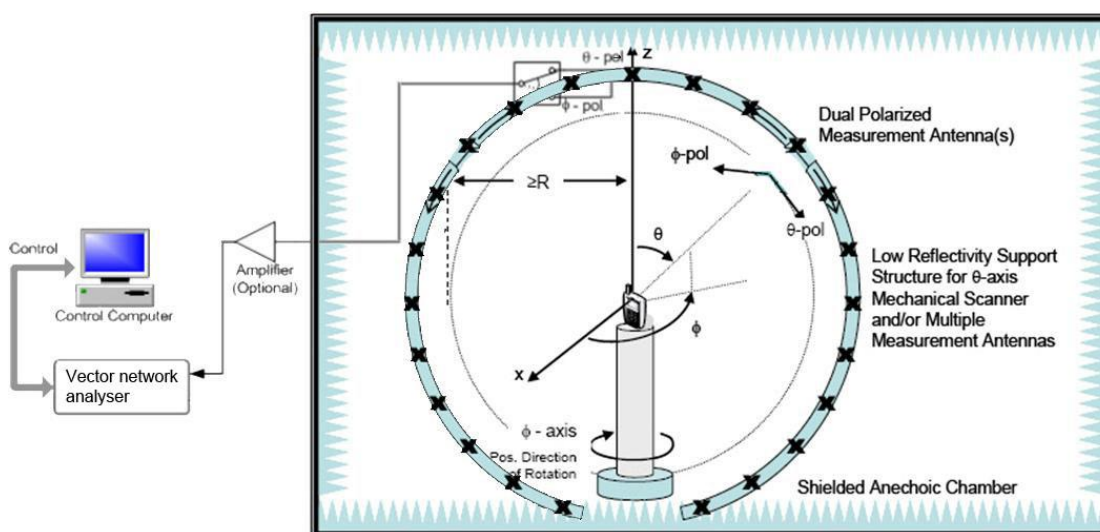
Environment Parameter	Selected Values During Tests			
	Ambient Pressure(KPa)	Temperature(°C)	Voltage	Relative Humidity (%)
Normal Temperature, Normal Voltage (NTNV)	101	25	N/A	50

4.2 Test Equipment List

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
SG24 Multi-probe Antenna Measurement System	SATIMO	SG24-L	1101855-0001	2021.11.12	2024.11.11
Vector Network Analyzer	Agilent	E5071B	MY42404001	2022.04.02	2023.04.01
Description	Manufacturer	Name		Version	
Test Software	MVG	SPM		V 1.8	

4.3 Test Setup

4.3.1 Antenna gain, efficiency and radiation pattern test setup



ANNEX A TEST RESULTS

A.1 Gain and Efficiency

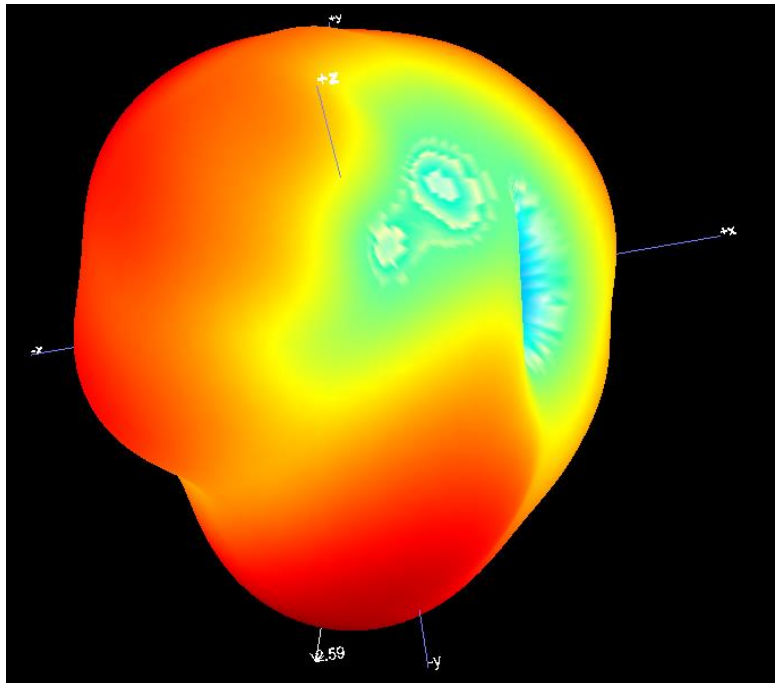
Frequency	Gain (dBi)	Efficiency (%)
2400MHz	2.59	62%
2402MHz	2.59	62%
2404MHz	2.56	61%
2406MHz	2.43	61%
2408MHz	2.41	60%
2410MHz	2.38	60%
2412MHz	2.35	60%
2414MHz	2.29	59%
2416MHz	2.41	60%
2418MHz	2.38	60%
2420MHz	2.32	59%
2422MHz	2.29	59%
2424MHz	2.29	60%
2426MHz	2.61	61%
2428MHz	2.59	61%
2430MHz	2.55	61%
2432MHz	2.56	61%
2434MHz	2.59	61%
2436MHz	2.60	61%
2438MHz	2.58	61%
2440MHz	2.61	61%
2442MHz	2.61	60%
2444MHz	2.60	60%
2446MHz	2.57	59%
2448MHz	2.55	59%
2450MHz	2.56	59%
2452MHz	2.55	59%
2454MHz	2.51	58%
2456MHz	2.53	58%
2458MHz	2.54	58%
2460MHz	2.52	58%
2462MHz	2.49	57%
2464MHz	2.49	57%
2466MHz	2.61	58%
2468MHz	2.64	58%
2470MHz	2.64	58%
2472MHz	2.66	58%
2474MHz	2.73	59%

2476MHz	2.78	59%
2478MHz	2.79	59%
2480MHz	2.79	58%
2482MHz	2.79	58%
2484MHz	2.81	58%
2486MHz	2.77	58%
2488MHz	2.74	58%
2490MHz	2.72	58%
2492MHz	2.73	58%
2494MHz	2.70	57%
2496MHz	2.54	57%
2498MHz	2.50	57%
2500MHz	2.48	57%

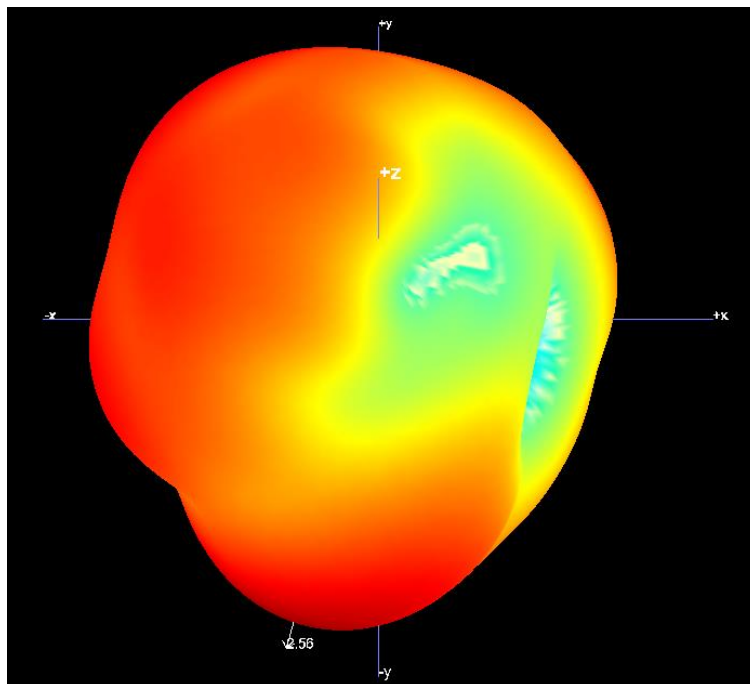
ANNEX B RADIATION PATTERN

B.1 3D Pattern

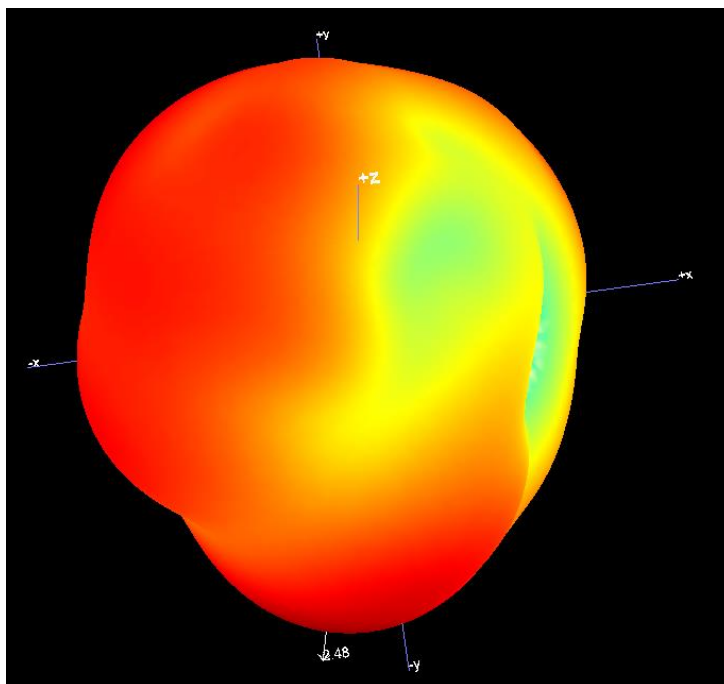
B1.1 3D Pattern for 2400MHz



B1.2 3D Pattern for 2450MHz

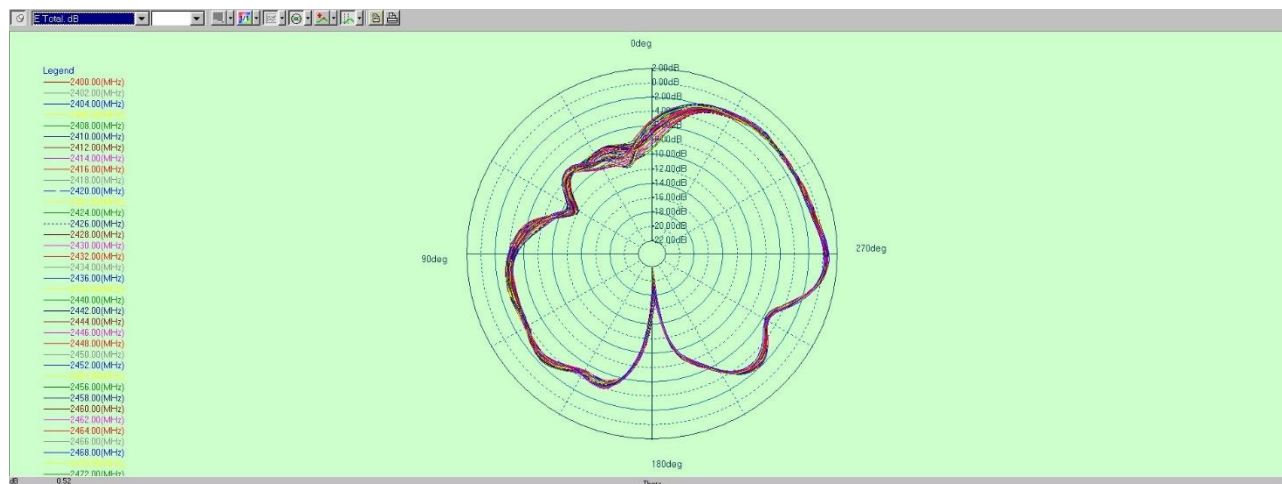


B1.3 3D Pattern for 2500MHz

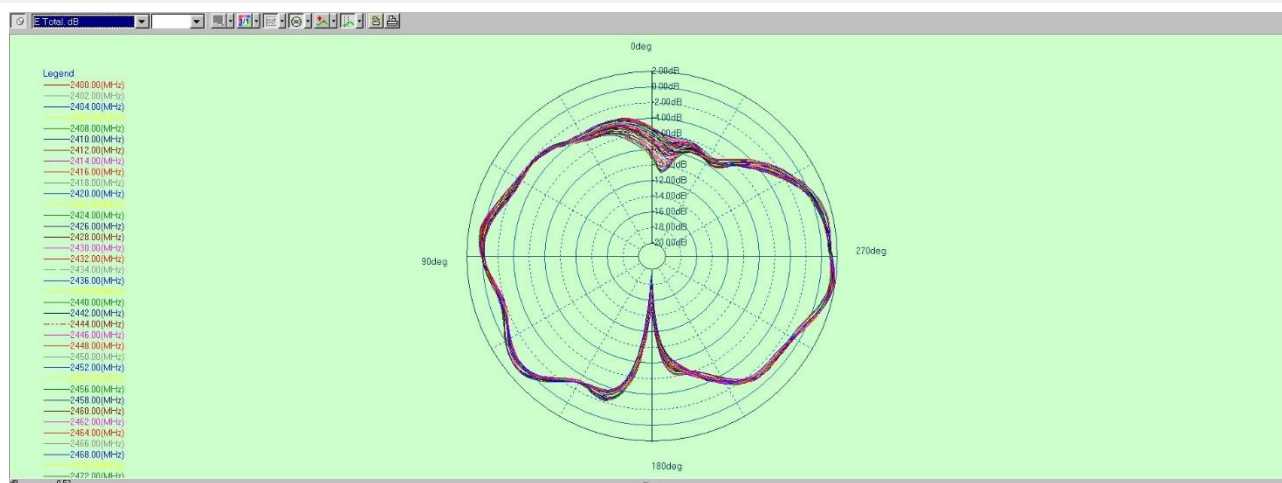


B.2 1D Radiation Pattern

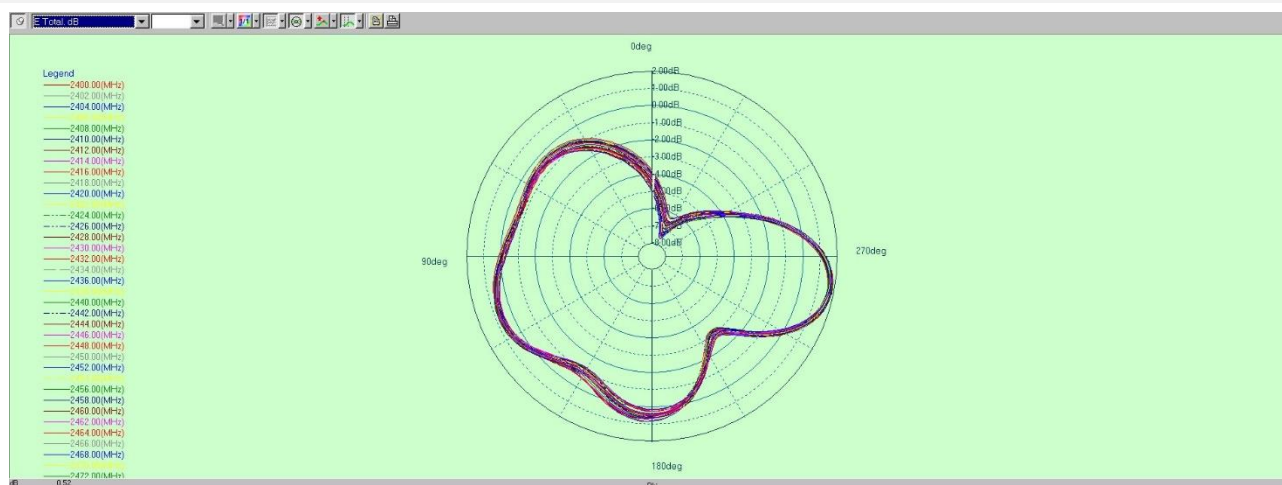
B2.1 PHI=0



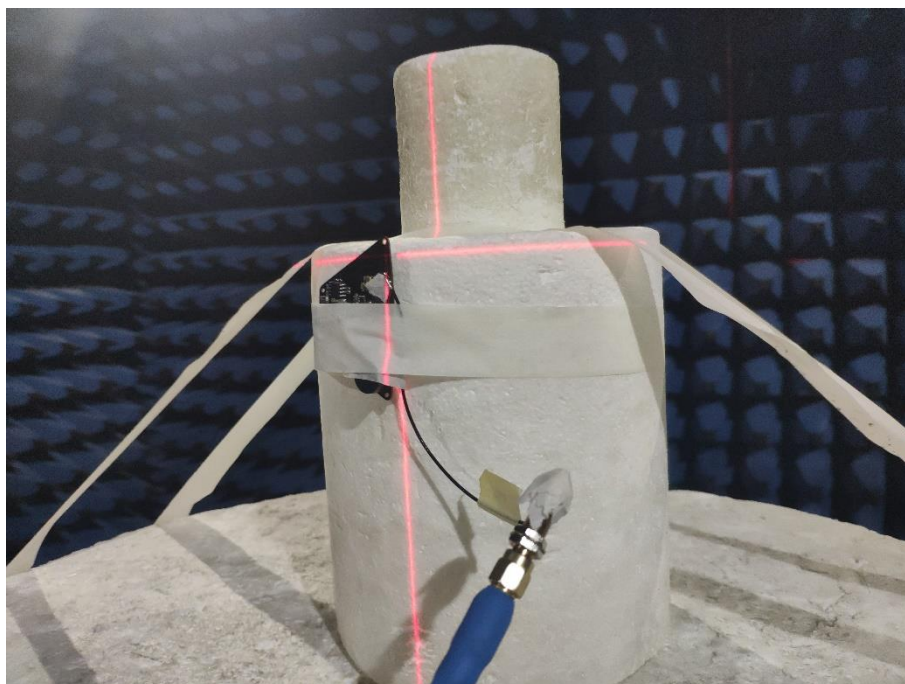
B2.2 PHI=90



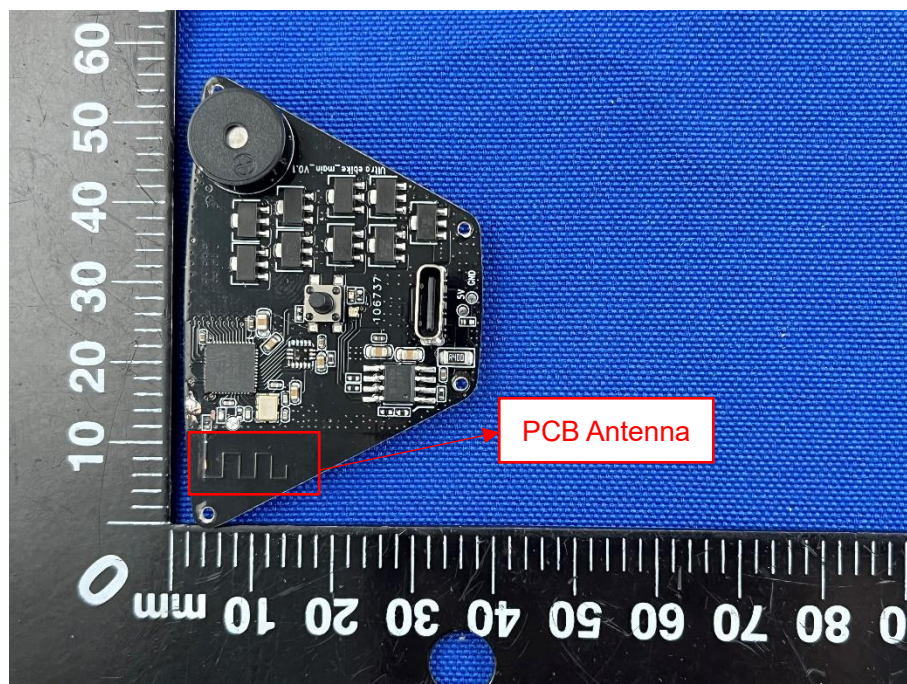
B2.3 THETA=90



ANNEX C TEST SETUP PHOTO



ANNEX D EUT PHOTO



Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
2. The report without China inspection body and laboratory Mandatory Approval (CMA) mark has no effect of proving to the society.
3. For the report with CNAS mark or A2LA mark, the items marked with "☆" are not within the accredited scope.
4. This report is invalid if it is altered, without the signature of the testing and approval personnel, or without the "inspection and testing dedicated stamp" or test report stamp.
5. The test data and results are only valid for the tested samples provided by the customer.
6. This report shall not be partially reproduced without the written permission of the laboratory.
7. Any objection shall be raised to the laboratory within 30 days after receiving the report.

--END OF REPORT--